Sea	rch .	Notes	•

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/709,267	WU, KE	
Examiner	Art Unit	
Linh V. Nauven	2810	

SEARCHED			
Class	Subclass	Date	Examiner
330	251,152 257,259 260,261	3/28/2005	LN
327	52,87 206	3/28/2005	LN
326	65,71 81	3/28/2005	LN
326	83	3/28/2005	LN
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		<u>. </u>	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
327	206	3/28/2005	LN
326	83	3/28/2005	LN

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
gate, self bias, current source, current sink, pull up, pull down, differential, bias	3/28/2005	LN
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